

EL979955240

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Priority Application Serial No. .... 10/232,295  
Priority Filing Date ..... August 30, 2002  
Inventor ..... Warren M. Farnworth et al.  
Assignee ..... Micron Technology, Inc.  
Priority Group Art Unit ..... 2829  
Priority Examiner ..... R. Robert  
Attorney's Docket No. ..... MI22-2524  
Title: Method and Apparatus for Testing Semiconductor Circuitry for Operability and  
Method of Forming Apparatus for Testing Semiconductor Circuitry for Operability

**INFORMATION DISCLOSURE STATEMENT**

References -- See attached Form PTO-1449

In compliance with 37 C.F.R. §§ 1.56, 1.97 and 1.98, your attention is directed to the United States patents and other references listed on the attached Form PTO-1449. No admission is made regarding whether all the submitted references are prior art.

The listed references were cited by, or submitted to, the Office in the parent, co-pending application of the above-identified application. The above-identified application is a divisional application of co-pending Application Serial No. 10/232,295, filed August 30, 2002, upon which the above-identified application relies for a priority date under 35 U.S.C. §120. Such prior disclosure is sufficient for the above-identified application as far as copies of the references are concerned. 37 C.F.R. §1.98(d) and MPEP §609(2). As a courtesy, copies of the foreign references and the articles are enclosed.

Citation of these references is respectfully requested.

Respectfully submitted,

Date: 3-17-04

  
D. Brent Kenady  
Reg. No. 40,045  
Customer No. 021567

Form PTO-1449		U.S. DEPARTMENT OF COMMERCE PATENT AND TRADEMARK OFFICE			ATTY. DOCKET NO. MI22-2524		SERIAL NO. Filed Herewith	
LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)					APPLICANT Warren M. Farnworth et al.			
					FILING DATE Filed Herewith		GROUP N/A	
U.S. PATENT DOCUMENTS								
*Examiner Initial		Document Number	Date	Name		Class	Subclass	Filing Date If Appropriate
	AA	3,412,456	11/68	Ebisawa				
	AB	3,469,019	9/69	Reinmann				
	AC	4,105,970	8/78	Katz				
	AD	4,141,055	2/79	Berry et al.				
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	AK	4,585,991	4/86	Reid et al.				
	AL	4,881,118	11/89	Niwayama et al.				
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		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AM	53171	03/91	Japan				
	AN	108350	05/91	Japan				
	AO	329314	08/89	European (EPO)				
	AP	5714838	09/82	Japan				
	AQ	2-5540	01/90	Japan				
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)								
	AR	Moto's Nakano "A Probe for Testing Semiconductor Integrated Circuits and a Test Method Using Said Probe." 25 March, 1991						
		Japanese Patent Office Disclosure No. Hei 3-69131, Filing No. Hei 1-205301, Filing Date August 8, 1989						
	AS							
	AT							
EXAMINER				DATE CONSIDERED				
*EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to applicant.								

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	AU	4,924,589	5/90	Leedy					
	AV	4,929,999	5/90	Hoebrechts et al.					
	AW	4,937,653	6/90	Blonder et al.					
	AX	4,952,272	8/90	Okino et al.					
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	AZ	5,420,520	5/95	Anschele et al.					
	BA	5,014,161	5/91	Lee et al.					
	BB	5,032,541	7/91	Sakamoto et al.					
	BC	5,045,780	9/91	Swart					
	BD	5,072,116	12/91	Kawade et al.					
	BE	5,103,557	4/92	Leedy					
	BF	5,137,461	8/92	Bindra et al.					
FOREIGN PATENT DOCUMENTS									
		Document Number	Date	Country		Class	Subclass	Translation	
								Yes	No
	BG	2232946	09/90	Japan					
	BH	410446	01/92	Japan					
	BI								
	BJ								
	BK								
OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)									
	BL								
	BM								
	BN								
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	BO	5,177,438	1/93	Littlebury et al.				
	BP	5,177,439	1/93	Liu et al.				
	BQ	5,196,251	3/93	Bakhru et al.				
	BR	5,206,585	4/93	Chang et al.				
	BS	5,235,140	8/93	Reele et al.				
	BT	5,239,260	8/93	Widder et al.				
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	BX	5,323,035	6/97	Leedy				
	BY	5,326,428	7/94	Farnworth et al.				
	BZ	5,334,804	8/94	Love et al.				
FOREIGN PATENT DOCUMENTS								
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							Yes	No
	CA							
	CB							
	CC							
	CD							
	CE							
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	CG							
	CH							
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	CI	5,353,195	10/94	Fillion et al.				
	CJ	5,367,253	11/94	Wood et al.				
	CK	5,402,077	03/95	Agahdel et al.				
	CL	5,419,807	05/95	Akram et al.				
	CM	5,431,328	07/95	Chang et al.				
	CN	5,478,779	12/95	Akram				
	CO	5,468,917	11/95	Brodsky et al.				
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	CQ	5,477,087	12/95	Kwakita et al.				
	CR	5,523,697	06/96	Farnworth et al.				
	CS	5,541,525	07/96	Wood et al.				
	CT	5,559,444	09/93	Farnworth et al.				
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							Yes	No
	CU							
	CV							
	CW							
	CX							
	CY							
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	CZ							
	DA							
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	DD	5,716,218	02/98	Farnworth et al.					
	DE	5,790,337	08/98	Schreiber et al.					
	DF	5,831,832	11/98	Gillette et al.					
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	DH	5,869,787	02/99	Akram					
	DI	6,002,266	12/99	Briggs et al.					
	DJ	6,093,643	07/00	Akram					
	DK	4,566,184	01/86	Higgins et al.					
	DL	5,838,160	11/17/1998	Beaman et al.					
	DM	4,571,540	2/18/1986	Stowers et al.					
	DN	4,116,523	09/26/78	Coberly et al.					
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	DQ								
	DR								
	DS								
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